









Organized by

IMAPS - International Microelectronics Assembly and Packaging Society 17 rue de l'Amiral Hamelin - 75016 Paris - France Tel: +33 (0) 7 88 75 59 86 imaps.france@orange.fr - www.france.imapseurope.org

Media Sponsor: YOLE

# Wednesday June 19th



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(Lars BOTTCHER, FRAUNHOFER IZM -

Welcome to MiNaPAD – Coffee & Soft drink sponsored by 8h15

9h00 Opening by Jean-Marc YANNOU (Auditorium)

9h10 Keynote: Mudasir AHMAD (IEEE – EPS Distinguished lecturer)

**Advanced Packaging for Artificial Intelligence Applications** 

9h45	SESSION A: AI Applications (Auditorium)  Detection and measurement of solder voids in X ray of led assembly with YOLO v8 (Yasser ALMEHIO, VALEO - France)	SESSION B: Attachment materials (Mont Blanc) The Application of Low Temperature Self- Assembly Sn Based Glue (Glenn LIN, ASE group - Taiwan)
10h15	Solder paste development using AI (Melanie MATHON, INVENTEC - France)	New Bare Copper Compatible Die Attach Developments Improving Reliability and Thermal at Lower Cost (Ruud De WIT, HENKEL – The Netherlands)

# 10h45 - 11h15 Exhibition Opening (Exhibition Hall) / Coffee break sponsored by

<b>SESSION C: Interconnections</b>	<b>SESSION D: PCB Substrates</b>
(Auditorium)	(Mont Blanc)
Integration of III-V GaN amplifiers of an antenna in	Advanced IC substrates – Challenges in the
package receiver in PCB-based embedding technology	manufacturing and supply chain
(Tekfouy LIM, FRAUNHOFER IZM - Germany)	(Roland STEIM, DYCONEX - Switzerland)
Alternative approach to Die-to-Wafer bonding utilizing atmospheric plasma cleaning (Daniel PASCUAL, ONTOS - USA)	Next Generation Packaging Materials for Challenging AI and Power Electronics Applications (Helmut KRONER, RESONAC - Germany)
Clips bonding using re-metallization techniques (Wilfrid AKLAMAVO, SERMA Microelectronics -	High Density Organic Substrates fir Chiplet and High Frequency Application

# TELEDYNE e2v | Semiconductors

**Germany**)

## 12h45 - 13h45 Lunch (Exhibition Hall) sponsored by

11h15

11h45

12h15

France)

	<b>SESSION E: Process Optimization 1</b>	SESSION F: Reliability 1
	(Auditorium)	(Mont Blanc)
13h45	An innovative deposition technology for	Robustness and environmental impact of under
	conductive & dielectric materials;	bump metallization for wafer level balling
	Multimaterials, Multilayers, Contactless High-	(Arnaud GARNIER, CEA LETI - France)
	Resolution High-Speed Deposition	
	(Stéphane ETIENNE, I-O-TECH, Israel)	
14h15	SWEET (Side Wall ExquisiteEnveloping	SACN doped Mn solder balls oxidation study for
	Technology) to protect WLSCP	BGA's reliability performance
	(Shih Chieh TANG, ASE group)	(Stelliane GROLIER LEE, STMicroelectronics -
		France)
14h45	Post plasma dicing clean in Batch spray	Experimental study of interfacial adhesion of
	equipment with sulfuric ozone mixtures	passivation/resin with shear test: first learnings
	(Moritz MITTERMAYR, SICONNEX - Austria)	(Marie DUGOR DENTONE, STMicroelectronics -
		France)



# 15h15 – 15h45 Exhibition / Coffee break sponsored by

**SESSION G: Dicing / Picking SESSION H: Flip Chip Process** (Auditorium) (Mont Blanc) 15h45 Plasma Singulation of Single Power Diodes Bonded by Development of a dipping process for silver Intermetallic Eutectic Technique sintered flip chip interconnexion (Sabrina ROZA-ORTIZ, PLASMATHERM - USA) (Céline FEAUTRIER, CEA LETI - France) 16h15 Latest approaches of dicing and grinding for Flux less soldering in activated hydrogen semiconductor device manufacturing atmosphere (Jeff BLAIR, SIKAMA - USA) (Benjamin BERNARD, DISCO - Germany) Displacement mechanisms of polymer 16h45 Industrial Approach for Plasma Dicing: Advances and adhesives used in the flip chip interconnected Challenges structures (Lucile BROUSSOUS, STMicroelectronics – France) (Nacer AITMANI, CEA LETI - France)

(Leslie LEA, PLASMATHERM - USA)

Precision plasma dicing of wafers

Innovative interconnect material for semiconductor assembly and advanced packaging

(Sze Pei LIM, INDIUM – United Kingdom)

17h45 – 18h30 Exhibition Hall

17h15

20h00: Dinner - Grenoble downtown

(15 minutes by walk from WTC – 1.4 kms)

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# Thursday June 20th

#### 8h30 - Opening exhibition and conferences

9h10 Keynote: Thomas ROMONT (Senior PCB Expert, IFTEC - France)

IPC Designers Council France - What are our common Challenges for Future?

Session J: Power Management (Auditorium)

Session K: Characterization (Mont Blanc)

**09h45** Understanding Criticality of Thermal

Performance in Thermal Interface Material for

**Automotive Applications** 

(Rodrigo AGUILAR, HENKEL – The Netherlands)

Dual blocks QFN warpage characterization (Federico LEONE, STMicroelectronics - Italy)

**10h15** Packaging and reliability challenges for

Innovative Automative Grade current sensors

(Alastair ATTARD, UTAC - Switzerland)

Die bending methodology to explore Deep Trench Isolation crack initiation risk in Backside Imager Sensors

(Caroline MOUTIN, STMicroelectronics - France)

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#### 10h45 - 11h15 Exhibition & Coffee break (Exhibition Hall) sponsored by



Session L: Process Optimization 2
(Auditorium)

(Auditorium)

In Situ characterization of plasma species for process optimization and improvement

(Djamila CHOU, STMicroelectronics - France)

**11h45** Direct silicon wafer bonding outside cleanroom

conditions

11h15

13h45

14h15

(Tobias BUCHMANN, DTU Electro - Denmark)

**12h15** Two steps collective bonding, from dicing-tape

to device over 10000 UPH

(Aurélien GRIFFART, SET - France)

Session M: Sustainability (Mont Blanc)

Fabrication of low density3D PCB using piezo-

ink jet and 6 axis robots

(Davide BENNEVENTI, INPG - France)

High Precision Capillary Printing (HPCAP) and its

sustainable value in electronics

(Julien VITIELLO, HUMMINK - France)

Sustainable and circular PCB using

biobased/biodegradable substrates and metals

bioleaching

(Vincent GRENNERAT, INPG CROMA - France)

THE NEW VALUE FRONTIER

## 12h45 - 13h45 Lunch & Exhibition (Exhibition Hall) sponsored by



Session N: Molding process (Auditorium)

Environment-friendly Epoxy Molding Compounds for Semiconductors and

Automotive

(Takahiro WATANABE, Sumitomo Bakelite Co.

Ltd - Japan)

Advanced Mold Design Solutions to Counteract Surface Discoloration in Flip Chip Encapsulation

(Shih Kun LO, ASE group - Taiwan)

Session O: Reliability 2 (Mont Blanc)

Enhanced Board Level Reliability Method for High Performance Automotive BGA Packages (Nohora CAICEDO, STMicroelectronics -

France)

The Effects of Voids on Solder Joint Reliability in

First Level Interconnect

(Sze Pei LIM, INDIUM – United Kingdom)

# Session P: Interposer 2.5D TSV 3D (Auditorium) 14h55 Design and verification of a 2.5 Heterogeneous Integration Platform (Jeroen SCHELKENS & Dimitrios TSIAKOS, IMEC - Belgium) 15h25 Unlocking the Trends and Challenges in Advanced 3D Heterogeneous Integration Manufacturing (Rayane MAZARI, YOLE Group - France) 15h50 Hermetically sealed glass interposer platform for photonics integrated circuits (Kevin KROEHNERT, FRAUNHOFER IZM - Germany) 16h15 Si Based integrated passive devices for Sub 6G SiP (Mark AZZOPARDI, JCET group - Switzerland)

16h45 Closing MiNaPAD 2024 Conference by Jean-Marc YANNOU (Auditorium)

# **List of Exhibitors**

<b>Booth number</b>	Company
1	IMAPS - PACK4EU
2	ASE
3	EMPC - IEEE
4	NANOTEC
5	ONTOS
6	CDS - NAMICS
7	MICROLIGHT 3D
8	GS SWISS PCB
9	ELEMCA
10	METRONELEC
11	MICON GLOBAL
12	KYOCERA
13	SET
14	NITERRA
15	ACCELONIX
16	AEMTEC
17	EGIDE
18	MST
19	TAIPRO
20	ISP SYSTEM
21	BT ELECTRONICS
22	TELEDYNE E2V
23	HYBRID
24	FINETECH
25	MICROWORLD
26	SERMA Microelectronics
27	ELECTRON MEC
28	HEF Groupe
29	CEA
30	SYNERGY CAD
31	PROTAVIC
32	DISCO
33	YOLE

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# **IMAPS BANK REFERENCES**

LCL VERSAILLES ST LOUIS - IBAN FR 49 3000 2089 0007 9088 G25 - Code BIC : CRLYFRPP